



Title: **Lot Level HAST Qualification Requirement Change**

Document type: **Product and/or Process Change Notification**

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Author: Josh Cortman

Owner: Josh Cortman

Approver(s): Todd McMullin  
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## 1. Type of Change (Major or Minor)

Minor

## 2. Change Description

The following changes are being made to better align Apogee Semiconductor's internal QCI flow with MIL-PRF-3585 group D3c requirements for QML class P lot level qualification. This is a lot level screening change and does not impact the inline processing of production material.

**Change 1:** Change in lot level qualification from biased highly accelerated temperature and humidity stress test (HAST) per JESD22-A110 (condition **A**) to biased HAST per JESD22-A110 (condition **B**)

**Change 2:** Addition of unbiased HAST per JESD22-A118 condition B as an additional option for lot level qualification.

## 3. Impact on Product and/or Process

None

## 4. Justification for Change

Alignment with MIL-PRF-3585 group D3c requirements for QMLP lot level qualification.

## 5. Change Risk Assessment

Low - alignment with industry standards

## 6. Qualification Plan

N/A - No change to material

## 7. Qualification Report

N/A - No change to material

## 8. Summary

See change description

## 9. Impacted Device - Document - Process List

This change applies to all A/B/C grade devices. Go to <https://apogeesemi.com/products/> for a full list of impacted products.

## 10. Sample Availability Date and Projected Production Shipment

**Proposed first ship date for change:** August 15th, 2024

**Identification of change:** QCI documentation for A/B/C grade lots will detail the HAST testing conducted on each specific lot.

## 11. File Attachment